

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: R. Japp et al

Group Art Unit:

Endicott Interconnect Technologies, Inc.

Examiner:

: IP Law, 0099/257-4 AA12

Serial No.:

: 1701 North Street

Filed: Herewith

Endicott, New York 13760

mid. Herewith

Title: DIELECTRIC COMPOSITION FOR FORMING

DIELECTRIC LAYER FOR USE IN CIRCUITIZED SUBSTRATES

Commissioner For Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

INFORMATION DISCLOSURE STATEMENT/CERTIFICATION

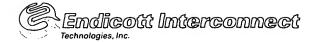
For ensuring compliance with Applicant's/Applicants' duty of disclosure under 37 CFR § 1.56, the undersigned hereby submits the documents listed on the attached Form PTO-1449 for consideration by the Examiner in charge of the above-identified patent application.

The listing of these documents is not to be construed as an admission that such is actually prior art with respect to the invention of the present application and is not to be construed that such is material with respect to the present invention.

[] U.S. patent applications which Applicant/Applicants considers/consider to be related to the above-identified application.



[]	A concise explanation of the relevance of the non-English language documents is attached:
[]	The relevance of the documents is indicated on the enclosed copy of the Search Report for the priority application
	These documents are being submitted (check only one of the next four boxes):
[X]	within three months of the filing of the above U.S. national application or of the date of entry of the U.S. national stage in an International Patent Application (no fee is due);
[]	before receiving a first Office Action on the merits of the above-identified patent application (no fee is due);
[]	following receipt of a first Office Action, but before issuance of a Final Office Action or a Notice of Allowance (if this box is checked, the fee box below or one of the last two boxes must be checked);
	<u>OR</u>
[]	following receipt of a Notice of Allowance or a Final Office Action (if this box is checked, the fee box and one of the last two boxes also must be checked).



CERTIFICATION

[]	The undersigned certifies that each item of this information is being submitted within
		three months of the date it was first cited in any communication from a foreign patent
		office in a counterpart foreign application.

[] The undersigned certifies that no item of information contained in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned, after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR § 1.56(c) more than three months prior to the filing of this information disclosure statement.

Respectfully submitted,

Lawrence R. Fraley

Attorney for Applicant/Applicants

Reg. No. 26,885

Telephone:

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561-745-2741

FORM PTO 1449 (Modified)			ATTY.	DOCK	ET NO. EI-	-2-04-005	SE	RIAL NO.		N/2	4		1		
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT			1	APPLIC	ANT	R. Japp et a	1								
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INITALS			NUMB	ER	DAT		NAME	 			CLASS	SUBCL	ASS	DATE	
		AA	3,953,50	56	04/7	6	Gore								
		AB	3,962,63	53	06/7	6	Basset								
		AC	4,187,3	90	02/8	0	Gore								
	4	AD	4,482,5	16	11/8	4	Bowman	et al							
	4	AE	4,579,7	72	04/8	6	Bhatt et	al							
	AF 4,642,160		50	02/8	7	Burgess									
	4	AG	4,675,78	89	06/8	7	Kuwabar	ra et al							
	4	AH	4,713,13	37	12/8	7	Sexton	-							
	4	ΑI	4,783,34	45	11/8	8	Kleeberg	g et al							
	1	AJ	4,864,72	22	09/8	9	Lazzarin	i et al							
	1	AK	5,129,14	1 2	07/9	2	Bindra e	t al							
		AL	5,229,5	50	07/9	3	Bindra e	t al							
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not

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considered. Include copy of this form with next communication to applicant.

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FORM PTO 14	449 (M	odified)	ATTY. DOCK	ET NO. EI-2-04-005	SERIAL NO.	N/A	
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT			APPLICANT	R. Japp et al			
Page _2 of5			FILING DATE	HEREWITH	GROUP	N/A	
				u. s. patent docui	MENTS		
EXAMINER		DOCUMENT					FILING
INITALS	J	NUMBER	DATE	NAME	CLASS	SUBCLASS	DATE
	AA	5,246,817	09/93	Shipley			
	AB	5,368,921	11/94	Ishii et al			
	AC	5,376,453	12/94	von Gentzkow et al			

Alpaugh et al

Shimoto et al

Capote et al

King et al

Nagai et al

Alpaugh et al

Nakayama et al

Dalman

von Gentzkow et al

AD

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AF

AG

AH

ΑI

ΑJ

ΑK

AL

5,418,689

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5,565,267

5,648,171

5,652,055

5,670,262

5,677,045

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5,726,863

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03/88

FOREIGN PATENT DOCUMENTS

EXAMINER INITALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM						
	AN						
	AO						
	AP						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

EXAMINER	DATE CONSIDERED

FORM PTO 14	149 (M	odified)	ATTY, DOCK	ET NO.	EI-2-04-005	SERIAL NO		N/A	
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT			APPLICANT]	R. Japp et al				
Page3 of5			FILING DATE		HEREWITH		GROUP	N/A	
				U.S.	PATENT DOC	UMENTS			
EXAMINER INITALS		DOCUMENT NUMBER	DATE	NAM	Œ		CLASS	SUBCLASS	FILING DATE
	AA	5,814,405	09/98	Branc	ea et al				
	AB	5,981,880	11/99	Appe	lt et al				
	AC	6,018,196	01/00	Nodd	in				
	AD	6,042,685	03/00	Shina	da et al				

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Boyko et al

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Sylvester

Fischer

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ΑF

AG

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT R. Japp et al		
Page _4 of5	FILING DATE HEREWIT	TH GROUP	N/A

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	AA	6,405,431 B1	06/02	Shin et al			
	AB	6,506,979 B1	01/03	Shelnut et al			
	AC	6,541,589 B1	04/03	Baillie			
	AD	6,586,687 B2	07/03	Lee et al			
	AE	US2002/0150673	10/02	Thorn et al			
	AF	US2002/0170827	11/02	Furuya			
	AG	US2002/0172019	11/02	Suzuki et al			
	AH	US2002/0190378	12/02	Hus et al			
	AI	US2003/0022013	01/03	Japp et al			
	AJ						
	AK						
	AL						

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EXAMINER INITALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AM	JP 56049271	05/81	Japan			Abstract
,	AN	JP 7086710	03/95	Japan			Abstract
	AO	JP 7097466	04/95	Japan			Abstract
	AP	JP 8092394	04/96	Japan			Abstract

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	AM	JP2	001015912A2	01/01		Japan						Abstract	
	AN	JP20	002223070A2	08/02		Japan			<u> </u>			Abstra	act
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